

Title (en)

METHOD FOR DETERMINING THE THICKNESS OF A THIN LAYER BY MULTI-WAVELENGTH INTERFEROMETRY AND CORRESPONDING COMPUTER PROGRAM PACKAGE, STORAGE MEANS AND SYSTEM

Title (de)

VERFAHREN ZUR BESTIMMUNG DER DICKE EINER DÜNN SCHICHT DURCH MULTIWELLENLÄNGENINTERFEROMETRIE UND ZUGEHÖRIGE COMPUTERPROGRAMMPAKET, SPEICHERMITTEL UND SYSTEM

Title (fr)

PROCÉDÉ DE DÉTERMINATION DE L'ÉPAISSEUR D'UNE COUCHE MINCE PAR INTERFÉROMÉTRIE MULTI-LONGUEUR D'ONDE, PRODUIT PROGRAMME D'ORDINATEUR, MOYEN DE STOCKAGE ET SYSTÈME CORRESPONDANTS

Publication

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Application

**EP 15807675 A 20151209**

Priority

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- EP 2015079178 W 20151209

Abstract (en)

[origin: WO2016091983A1] A method and system are provided for determining the thickness of a thin layer deposited on the surface of a reflective substrate, by means of a multi-wavelength device in a configuration equivalent to a Michelson interferometer. The method consists in: generating (20) an array of collimated light beams intended to illuminate the surface of the thin layer and that of the planar mirror, each beam having a distinct wavelength; occulting (21) the measurement arms, preventing the collimated light beams from being received by the object to be measured, and obtaining (22) a reference image representative of the light intensity issued from the planar mirror; occulting (23) the reference arm, preventing the collimated light beams from being received by the planar mirror, and obtaining (24) a measurement image representative of the light intensity issued from the object to be measured; and determining (25) the thickness of the thin layer from the measurement and reference images obtained.

IPC 8 full level

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